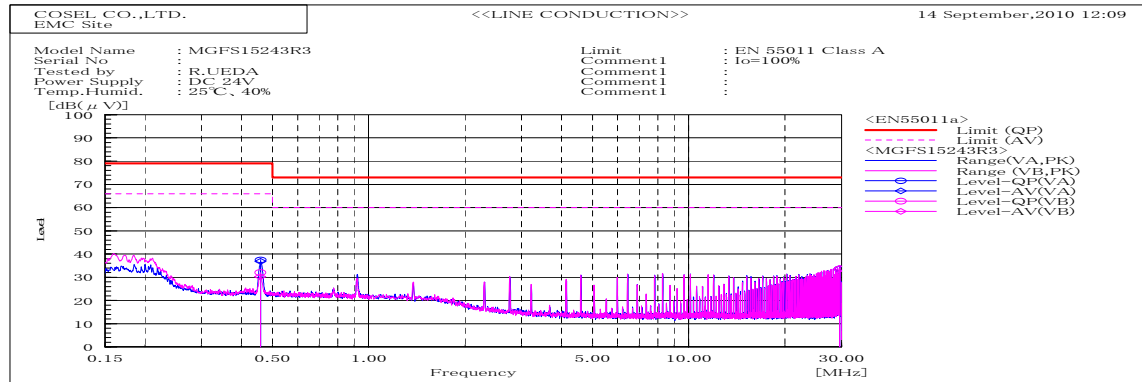
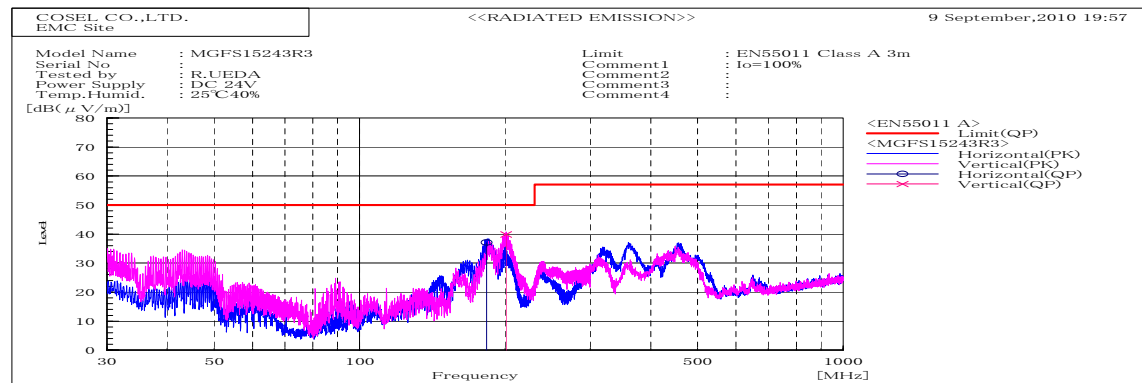


DATA SHEET		Date	21-Sep-10
Model	MGFS15243R3	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Ueda



Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.45824		VB	22	20.2	10	32	30.2	79	66	47	35.8	Pass	
0.45935		VA	27.4	26.8	10.1	37.5	36.9	79	66	41.5	29.1	Pass	
29.64215		VA	23	23.1	10.6	33.6	33.7	73	60	39.4	26.3	Pass	
29.64275		VB	22.6	22.8	11	33.6	33.8	73	60	39.4	26.2	Pass	

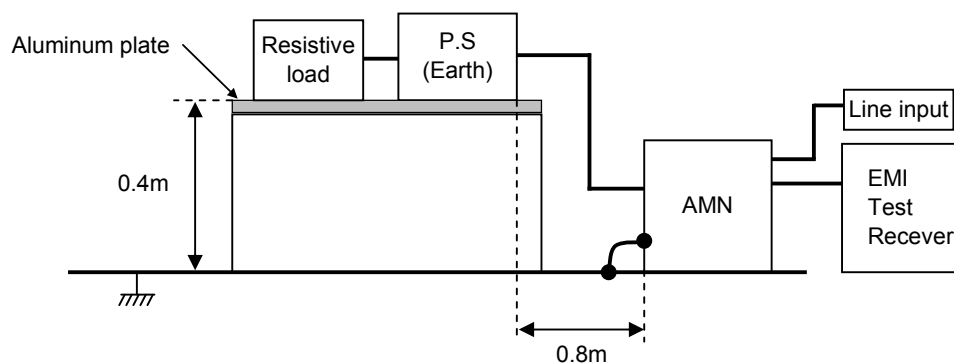


Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
182.893	H	Stable	59.3	-22.2		37.1		50	12.9	Pass	150	356	
200.78	V	Stable	61.9	-22		39.9		50	10.1	Pass	122	228	

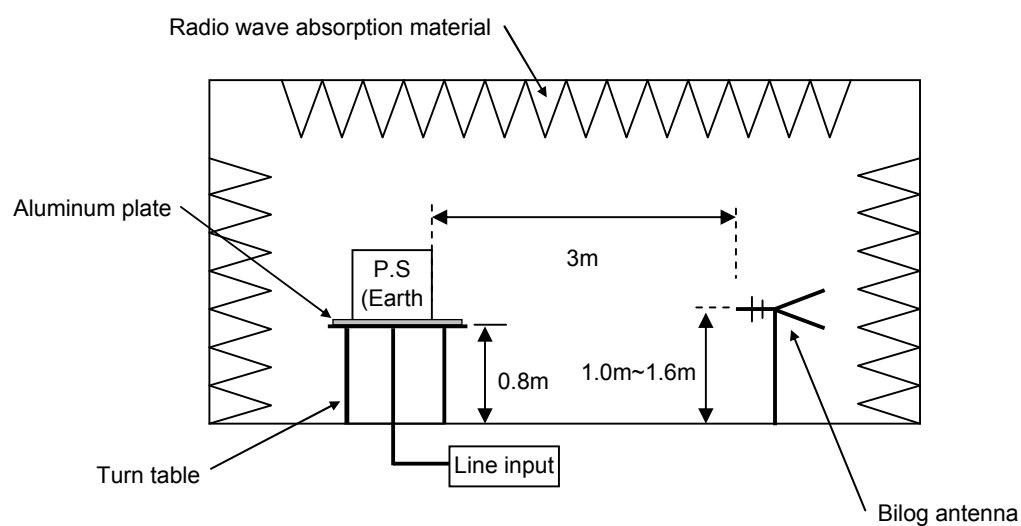
## DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

### 1. Line conduction



### 2. Radiated emission



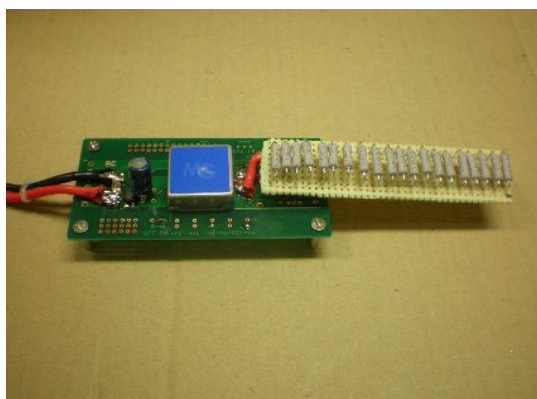


## Conditions

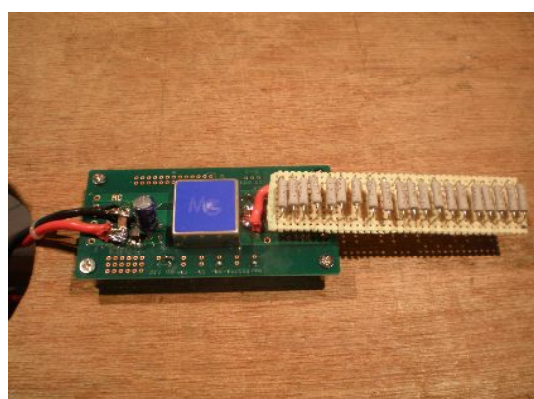
Test : EMI  
Model Name : MGFS1524□□/MGFW1524□□

○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



○Testing circuitry

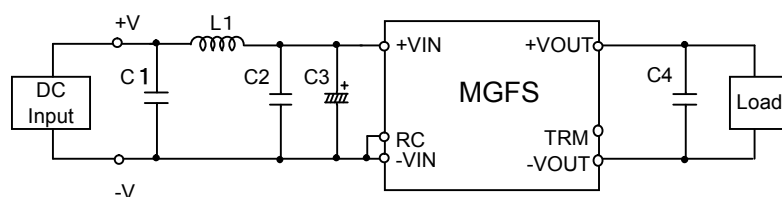


Fig.1 Testing circuitry 1

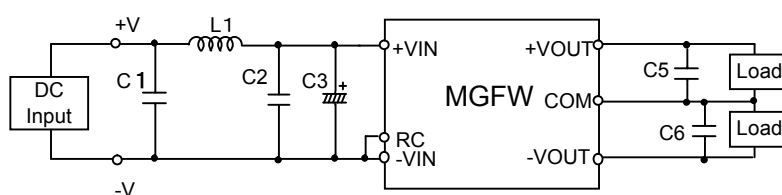


Fig.2 Testing circuitry 2

L1	:	0.5uH	CI4C-0R5	(KORIN ELECTRONICS)
C1,C2	:	50V 6.8 $\mu$ F	C4532X7R1H685MT	(TDK)
C3	:	50V 100 $\mu$ F	LXZ50VB100M	(NIPPON CHEMI-CON)
C4,C5,C6	:	25V 22 $\mu$ F	CM32X5R226K25A	(KYOCERA)